

**Notice of References Cited**

Application/Control No.

10/029,972

Applicant(s)/Patent Under  
Reexamination  
SEPPALA ET AL.

Examiner

Nhan T Le

Art Unit

2685

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,181,921	01-2001	Konisi et al.	455/186.2
	B	US-6,597,918	07-2003	Kim, Sung-Sik	455/466
	C	US-2002/0055350	05-2002	Gupte et al.	455/412
	D	US-6,470,178	10-2002	Cummings-Hill et al.	455/186.1
	E	US-6,408,188	06-2002	Park, Dong-Hee	455/466
	F	US-4,481,382	11-1984	Villa-Real, Antony-Euclid C.	455/556.1
	G	US-2003/0069032	04-2003	Jarvi et al.	455/466
	H	US-2002/0137552	09-2002	Cannon et al.	455/567
	I	US-2001/0009857	07-2001	Vanttinen, Veijo	455/456
	J	US-6,282,412	08-2001	Lyons, Francis R. X.	455/186.1
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.